

[54] TEST APPARATUS FOR DETERMINING RESISTANCE TO LIGHT AND WEATHER INFLUENCES

[75] Inventors: Helmut Schmid, Krefeld; Martin Bock, Duisburg; Günther Kämpf, Krefeld, all of Fed. Rep. of Germany

[73] Assignee: Original Hanau Heraeus GmbH, Hanau, Fed. Rep. of Germany

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Primary Examiner—F. L. Evans

Attorney, Agent, or Firm—Frishauf, Holtz, Goodman & Woodward

[57] ABSTRACT

To provide for more reliable determination of resistance of sample surfaces to light and weather influences, test apparatus is equipped with a radiation-measuring device. A portion of radiation used for testing is guided to the measuring device, by quartz guides, spectrally dispersed, and measured as to intensity and/or dosage in one or several pre-selected spectral regions. Tests may use natural or artificial radiation, and a measuring device may be stationary or movable relative to a radiation source.

5 Claims, 8 Drawing Figures

